TOSHIBA MOS MEMORY PRODUCTS

TC524257P/Z/J-10, TC524257P/Z/J-12

DESCRIPTION

The TC524257P/Z/J is a CMOS Multiport memory equipped with a 262,144-word × 4 bit dynamic random access memory(RAM) port and a 512-word × 4 bit static serial access memory(SAM) port. In addition to the conventional DRAM operation modes, the TC524257P/Z/J features a logic function and a write-per-bit function on the RAM port; Bi-directional transfer capability between the DRAM memory array and the SAM data register and a high speed serial read/write capability on the SAM port. The RAM port and the SAM port can be accessed independently except when data is being transferred between them internally. The TC524257P/Z/J is fabricated using TOSHIBA's CMOS silicon gate process technology as well as advanced circuitry to provide low power dissipation and wide operating margin. Multiplexed address inputs and a common input/output organization allow the TC524257P/Z/J to be housed in a standard 28-pin, 400-mil wide plastic DIP and 400-mil height ZIP, and in a standard 32-pin 400-mil wide plastic SOJ. System oriented features include a single 5V±10% power supply operation and compatibility with high performance schottky TTL logic.

FEATURES

	ITEM	TC52425	57P/Z/J
		-10	-12
^t RAC	RAS Access Time (Max.)	100ns	120ns
^t CAC	CAS Access Time (Max.)	50ns	60ns
^t RC	Cycle Time (Min.)	190ns	220ns
^t PC	Page Mode Cycle Time(Min.)	90ns	105ns
^t SCA	Serial Access Time (Max.)	25ns	35ns
tscc	Serial Cycle Time (Min.)	30ns	40ns
I _{CC1}	RAM: Operating Current (SAM: Standby)	70mA	60mA
ICC2A	SAM Operating Current (RAM: Standby)	50mA	45mA
I _{CC2}	RAM/SAM Standby Current	10	mA

· Organization

RAM port: 262,144 words × 4 bits SAM port: 512 words × 4 bits

• Single power supply of 5V \pm 10% with a builtin V_{BB} generator

- Read-Modify-Write, CAS before RAS refresh, Hidden refresh, Page mode, Write-Per-Bit, Raster operation, Read transfer, Write transfer, Serial read, Serial Write capability.
- $\boldsymbol{\cdot}$ All inputs and outputs TTL compatible
- 512 refresh cycle/Sms

• Package

TC524257P: 0.4 inches 28 pins standard

Plastic DIP

TC524257Z: 0.4 inches 28 pins standard

Plastic ZIP

TC524257J: 0.4 inches 32 pins standard

Plastic SOJ

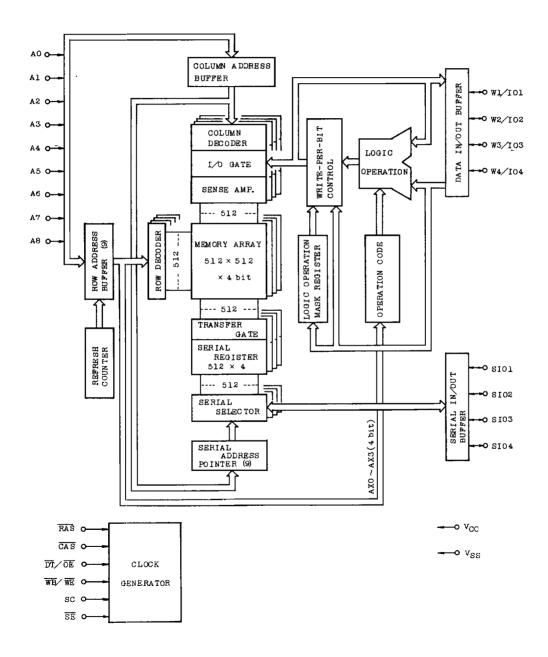
PIN NAMES

A0 ∿ A8	Address Inputs
RAS	Row Address Strobe
CAS	Column Address Strobe
DT/OE	Data Transfer/Output Enable
WB/WE	Write Per Bit/Write Enable
W1/IO1 ~ W4/IO4	Write Mask/Data IN, OUT
SC	Serial Clock
ŠE	Serial Enable
SIO1 ∿ SIO4	Serial Input Output
VCC	Power (+5V)
V _{SS}	Ground
N.C.	No Connection

PIN CONNECTION (TOP VIEW)

Plast	ic DIP	Plastic ZIP	Plasti	c SOJ
sc (1	28 V _{SS}	N.C. 17 [2 W3/103	N.C. 1	32) V _{SS}
SI01 [2	2705104	W4/104 3 F4 SE	ន េក្ ខ	31) ^V ธธ
SI02 [3	26 1 8103	S103 5 3 G104	SI01 [3	30 SI04
DT/OEC4	25] SE	Vss 7 Fa sc	SI02 [4	29 1 SI03
w1/101 [5	24 W4/I04	SIOL	DT/OEC5	28 SE
w2/102 [6	23 W3/103	DT/OE 11 12 W1/101	W1/101 6 5	27 W4/104
WB/WEC7	22 0 N.C.	W2/102 II WB/WE	w2/102 6 7	26 W3/I03
и.С. С 9	21 CAS	N.C. 15 76 3AS	WB∕WEC8	250 N.C.
RAS [9	20 р м.с.	A8 17 18 A5	N.C. 7	24 CAS
A8 🗖 10	19) AO	A5 19: 533	RASE 10	23) N.C.
A6 🕻 🗓	18 1 Al	VOO[2] 63 47	A8 C 11	22 5 AO
A5 🕻 12	17) A2	A3 23 [24] A2	A6 [12	21 1 A1
44 [13	16 1 A3	A1 25 72 40	A5 [13	20 j A2
V _{CC} [14	15) A7	N.C. 27 28 5AS	A4 []14	19 0 A3
			V ₃₀ C 15	18) A7
			VCC I 16	17) N.C.

BLOCK DIAGRAM



ABSOLUTE MAXIMUM RATINGS

SYMBOL	ITEM	RATING	UNITS	NOTES
V _{IN} V _{OUT}	Input Output Voltage	-1.0 ∿ 7.0	V	1
V _{CC}	Power Supply Voltage	-1.0 ~ 7.0	v	1
Topr	Operating Temperature	0 ∿ 70	°C	1
T _{stg}	Storage Temperature	-55 ∿ 150	°C	1
TSOLDER	Soldering Temperature • Time	260 • 10	°C•sec	1
PD	Power Dissipation	1	W	1
I _{OUT}	Short Circuit Output Current	50	mA	1

RECOMMENDED DC OPERATING CONDITION (Ta=0 ~ 70°C)

11200. # 72.72	DED DO OF ENDITEND CONDITION V					
SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNIT	NOTES
V _{CC}	Power Supply Voltage	4.5	5.0	5.5	v	2
VIH	Input High Voltage	2.4	_	6.5	V	2
VIL	Input Low Voltage	-1.0	_	0.8	V	2

DC ELECTRICAL CHARACTERISTICS (Vcc=5V±10%, Ta=0 ~ 70°C)

arnen or	TOTAL (DAM Dant)	SAM	1	TC524257P/ Z/J-10		TC524257P/ Z/J-12		NOTEC
SYMBOL	ITEM (RAM Port)	Port	MIN.	MAX.	MIN.	MAX.	UNITS	NOTES
I _{CC1}	OPERATING CURRENT	Standby	_	70	-	60		3,4
I _{CC1A}	(RAS, CAS Cycling: tRC=tRC MIN.)	Active	 -	110	-	100	m.A	3,4
I _{CC2}	STANDBY CURRENT	Standby	-	10	_	10	mA	
I _{CC2A}	(RAS, CAS=VIH)	Active	-	50	_	45	IILA	3,4
I _{CC3}	RAS ONLY REFRESH CURRENT	Standby	-	70	-	60	^	3
I _{CC3A}	(RAS Cycling, CAS=VIH: tRC=tRC MIN.)	Active	T-	110	-	100	m.A	3,4
I _{CC4}	PAGE MODE CURRENT	Standby	T -	60	-	50	mА	3,4
I _{CC4A}	(RAS=V _{IL} , CAS Cycling: t _{PC} =t _{PC} MIN.)	Active	-	100	-	90	(ILP1	3,4
I _{CC5}	CAS BEFORE RAS REFRESH CURRENT	Stadnby	-	70	-	60		3
I _{CC5A}	(CAS Before RAS Cycling:tRC=tRC MIN.)	Active	-	110		100	mA.	3,4
I _{CC6}	DATA TRANSFER CURRENT	Standby	I -	80		75	mΑ	3
I _{CC6A}	(RAS, CAS Cycling: tRC=tRC MIN.)	Active	-	130	-	120		3,4

SYMBOL	ITEM	MIN.	TYP.	MAX.	UNITS	NOTES
	INPUT LEAKAGE CURRENT (OV ≤ VIN ≤ 6.5V, All Other Pins Not Under Test=OV)	-10	0	10	μA	
I ₀ (L)	OUTPUT LEAKAGE CURRENT (Output is disabled, OV \(^{V}\)OUT \(^{5}.5V)	-10	0	10	μA	
	OUTPUT HIGH LEVEL VOLTAGE (Wi/IOi, SIOi IOUT=-2mA)	2.4	- _	-	V	
	OUTPUT LOW LEVEL VOLTAGE (Wi/IOi I _{OUT} =+2mA)	-	-	0.4	V	

ELECTRICAL CHARACTERISTICS AND RECOMMENDED AC OPERATING CONDITIONS

 $(V_{CC}=5V\pm10\%, Ta=0 \sim 70^{\circ}C)$ (NOTES 5, 6, 7)

SYMBOL	PARAMETER		24257P/ J-10		24257F/ 'J-12	IINITT	NOTES
OTTIBOL	ANGELLIA	MIN.	_	MIN.		UNII	NOTE
tRC	Random Read or Write Cycle Time	190		220			<u> </u>
tRWC	Read-Write Cycle Time	250		290		1	
t _{PC}	Page Mode Cycle Time	90		105			
tPRWC	Page Mode Read-Write Cycle Time	150		175	-		ļ
t _{RAC}	Access Time from RAS		100		120		8,14
tCAC	Access Time from CAS		50		60		8,14
tOFF	Output Buffer Turn-Off Delay	0	30	0	35		10
t _T	Transition Time (Rise and Fall)	3	35	3	35		7
t _{RP}	RAS Precharge Time	80		90			
t _{RAS}	RAS Pulse Width	100	10,000	120	10,000		
t _{RSH}	RAS Hold Time	50		60			
tCSH	CAS Hold Time	100		120			
t _{CAS}	CAS Pulse Width	50		60			
tRCD	RAS to CAS Delay Time	20	50	25	60		
tCRP	CAS to RAS Precharge Time	10		10			
tCPN	CAS Precharge Time	15		20		ns	
t _{CP}	CAS Precharge Time (Page Mode)	30		35			
tASR	Row Address Set-Up Time	0		0			
t _{RAH}	Row Address Hold Time	10		15			
^t ASC	Column Address Set-Up Time	0		0			
tCAH	Column Address Hold Time	20		25			
t _{AR}	Column Address Hold Time referenced to \overline{RAS}	70		85			
t _{RCS}	Read Command Set-Up Time	0		0			
tRCH	Read Command Hold Time	0		0			11
tRRH	Read Command Hold Time referenced to \overline{RAS}	10		10			11
tWCH	Write Command Hold Time	20		25			
tWCR	Write Command Hold Time referenced to \overline{RAS}	70		85			
tWP	Write Command Pulse Width	20		25			
tRWL	Write Command to RAS Lead Time	30		35			
tCWL	Write Command to CAS Lead Time	30		35			
t _{DS}	Data Set-Up Time	0		0			12
t _{DH}	Data Hold Time	20		25]		12
tRASP	RAS Pulse Width (Page Mode)	190	100,000	225	100,000	ĺ	

ELECTRICAL CHARACTERISTICS AND RECOMMENDED AC OPERATING CONDITION (Continued)

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SYMBOL	PARAMETER	1	257F/ -10	TC524 Z/J-	257P/ -12	UNITS	NOTES
		MIN.	MAX.	MIN.	MAX.		
tDHR	Data Hold Time referenced to RAS	70		85			
twcs	Write Command Set-Up Time	0		0		1	13
tRWD	RAS to WE Delay Time	125		150	***		13
t _{CWD}	CAS to WE Delay Time	75		90			13
t _{DZC}	Data to CAS Delay Time	0		0			
t _{DZO}	Data to $\overline{\text{OE}}$ Delay Time	0		0			
t _{OEA}	Access Time from $\overline{\text{OE}}$		25		30		
tOEZ	Output Buffer Turn-Off Delay from $\overline{\text{OE}}$	0	20	0	25	ns	10
t _{OED}	OE to Data Input Delay Time	20	-	25	,		
t _{OEH}	OE Command Hold Time	20		20			
t _{ROH}	RAS Hold Time referenced to $\overline{\text{OE}}$	20		20			
t _{CSR}	CAS Set-Up Time for CAS Before RAS Cycle	10		10			
t _{CHR}	CAS Hold Time for CAS Before RAS Cycle	20		20			
tRPC	RAS Precharge to CAS Active Time	0		0			
tCPT	$\overline{\text{CAS}}$ Precharge Time for $\overline{\text{CAS}}$ Before $\overline{\text{RAS}}$ Counter Test	40		50			
tREF	Refresh Period		8		8	ms	
twsr	WB Set-Up Time	0		0			
t _{RWH}	WB Hold Time	10		15			
t _{MS}	Write-Per-Bit Mask Data Set-Up Time	0		0			
tMH	Write-Per-Bit Mask Data Hold Time	10		15			
tTHS	DT High Set-Up Time	0		0			
tTHH	DT High Hold Time	10		15		1	
tTLS	DT Low Set-Up Time	0		0			
tTLH	DT Low Hold Time	10		15		ns	
t _{RTH}	DT Low Hold Time referenced to RAS (Real Time Read Transfer)	80		95	·	113	
^t CTH	DT Low Hold Time referenced to CAS (Real Time Read Transfer)	30		35			
t _{ESR}	SE Set-Up Time referenced to RAS	0		0			
tREH	$\overline{\mathtt{SE}}$ Hold Time referenced to $\overline{\mathtt{RAS}}$	10		15			
tTRD	DT to RAS Delay Time (Read Transfer)	0		0			
t _{RP}	DT Prechaege Time	30		35			
t _{RSD}	RAS to First SC Delay Time (Read Transfer)	100		120			

ELECTRICAL CHARACTERISTICS AND RECOMMENDED AC OPERATING CONDITION (Continued)

		TC524	257P/	TC524	257P/		
SYMBOL	PARAMETER	Z/J	-10	Z/J-		UNIT	NOTES
		MIN.	MAX.	MIN.	MAX.		
tCSD	CAS to First SC Dealy Time (Read Transfer)	50		60			
tTSL	Last SC to $\overline{\rm DT}$ Lead Time (Real Time Read Transfer)	5		10			
t _{TSD}	DT to First SC Delay Time (Read Transfer)	15		20			
tSRS	Last SC to RAS Set-Up Time (Serial Input)	30		40			
t SRD	RAS to First SC Delay Time (Serial Input)	25		30			
t _{SDD}	RAS to Serial Input Delay Time	50		60			
t _{SDZ}	Serial Output Buffer Turn-Off Delay from RAS (Pseudo Write Transfer)	10	50	10	60		10
tszs	Serial Input to First SC Delay Time	0		0			
t _{SCC}	SC Cycle Time	30		40			
^t sc	SC Pulse Width (SC High Time)	10		15			
t _{SCP}	SC Precharge Time (SC Low Time)	10		15		ns	
t _{SCA}	Access Time from SC		25		35		9
t _{SOH}	Serial Output Hold Time from SC	5		5			Ť
t _{SDS}	Serial Input Set-Up Time	0		0			
t _{SDH}	Serial Input Hold Time	20		30			
t _{SEA}	Access Time from SE		25		35		9
t _{SE}	SE Pulse Width	25		35	`		
t _{SEP}	SE Precharge Time	25		35			
^t SEZ	Serial Output Buffer Turn-Off Delay from SE	0	20	0	30		10
t _{SZE}	Serial Input to $\overline{\text{SE}}$ Delay Time	0		0			
tsws	Serial Write Enable Set-Up Time	5		10			
tSEH	Serial Write Enable Hold Time	15		20			
tSWIS	Serial Write Disable Set-Up Time	5		10			
tSWIH	Serial Write Disable Hold Time	15		20			

RASTER OPERATION WRITE CYCLE

ELECTRICAL CHARACTERISTICS AND RECOMMENDED AC OPERATING CONDITIONS

 $(V_{CC}=5V\pm10\%, Ta=0 \sim 70^{\circ}C)$ (NOTES 5, 6, 7)

SYMBOL	PARAMETER	1	TC524257P/ TC524257P/ Z/J-10 Z/J-12		UNIT	NOTES	
		MIN.	MAX.	MIN.	MAX.		
tFRC	Write Cycle Time	220		260			15
^t FRWC	Read-Write Cycle Time	280		330			15
t _{FPC}	Page Mode Write Cycle Time	120		145			15
^t FPRWC	Page Mode Read-Write Cycle Time	180		215			15
tFRAS	-RAS Pulse Width	130		160		ns	15
t _{FRSH}	RAS Hold Time	80		100			15
t _{FCSH}	CAS Hold Time	130		160			15
t _{FCAS}	CAS Pulse Width	80		100			15
tFRWL	Write Command to RAS Lead Time	60		75		Ī	15
t _{FCWL}	Write Command to CAS Lead Time	60		75		[15

CAPACITANCE (V_{CC} =5 $V\pm10\%$, f=1MHz, Ta=0 ~70 °C)

SYMBOL	PARAMETER	MIN.	MAX.	UNIT
CII	Input Capacitance (AO ^ A8)	-	- 8	
C ₁₂	Input Capacitance (RAS, CAS, DT/OE, WB/WE, SC, SE)	_	8	
c _{IO1}	Input/Output Capacitance (W1/IO1 ~ W4/IO4)	_	10	pF
C ₁₀₂	Input/Output Capacitance (SIO1 ~ SIO4)	-	10	1

NOTES:

- Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device.
- All voltages are referenced to V_{SS}.
- 3. These parameters depend on cycle rate.
- These parameters depend on output loading. Specified values are obtained with the output open.
- 5. Power must be applied to the RAS and DT/OE input signals to pull them "high" before or at the same time as the VCC supply is turned on. After power-up, a pause of 200 μseconds minimum is required with RAS and DT/OE held "high." After the pause, a minimum of eight (8) RAS and (8) SC dummy cycles must be performed to stabilize the internal circuitry, before valid read, write or transfer operations can begin. During the initialization period, the DT/OE signal must be held "high." If the internal refresh counter is used, a minimum (8) CAS-before-RAS initialization cycles are required instead of (8) RAS cycles.
- AC measurements assume t_T=5ns.
- 7. V_{IH} (min.) and V_{IL} (max.) are reference levels for measuring timing of input signals. Also, transition times are measured between V_{IH} and V_{IL} .
- 8. RAM port outputs are measured with a load equivalent to 2 TTL loads and 100pF.
- SAM port outputs are measured with a load equivalent to 2 TTL loads and 30pF. D_{OUT} comparator level: V_{OH}/V_{OL}=2.0V/0.8V.
- t_{OFF} (max.), t_{OEZ} (max.), t_{SDZ} (max.) and t_{SEZ} (max.) define the time at which the outputs achieve the open circuit condition and are not referenced to output voltage levels.
- 11. Either t_{RCH} or t_{RRH} must be satisfied for a read cycle.
- These parameters are referenced to CAS leading edge of early write cycles and to WB/WE leading edge in read-write cycles.
- 13. t_{WCS}, t_{RWD} and t_{CWD} are not restrictive operating parameters. They are included in the data sheet as electrical characteristics only. If t_{WCS} ≥ t_{WCS} (min.), the cycle is an early write cycle and the data out pin will remain open circuit (high impedance) throughout the entire cycle; if t_{RWD}≥t_{RWD} (min.) and t_{CWD}≥ t_{CWD} (min.), the cycle is a read-write cycle and the data out will contain data read from the selected cell: If neither of the above sets of conditions is satisfied, the condition of the data out (at access time) is indeterminate.
- 14. Operation within the t_{RCD} (max.) limit insures that t_{RAC} (max.) can be met. t_{RCD} (max.) is specified as a reference point only: If t_{RCD} is greater than the specified t_{RCD} (max.) limit, then access time is controlled by t_{CAC}.

DEVICE INFORMATION

RAM PORT OPERATION

Operation Truth Table

All operation modes of TC524257P/Z/J are determined by $\overline{\text{CAS}}$, $\overline{\text{DT}}/\overline{\text{DE}}$, $\overline{\text{WB}}/\overline{\text{WE}}$, and $\overline{\text{SE}}$ at the falling edge of $\overline{\text{RAS}}$. They are shown in the following tabel 1.

RAS	CAS	ADDRESS	DT/OE	WB/WE	SE	FUNCTION
Н	Н	*	*	*	*	Standby
	Н	Valid	H → L	Н	*	Read
	Н	Valid	н	H → L	*	Write
	Н	Valid(Row add.)	Н	*	*	RAS only refresh
	L	*	H(1)	H	*	CAS-before-RAS Refresh
T	Н	Valid	Н	L	*	Write-per-Bit
	L	Valid(A0 ∿ A3)	H(1)	L	*	Raster Operation Set-up
	Н	Valid	L	Н	*	Read Transfer
	Н	Valid	L	L	L	Write Transfer
	Н	Valid	L	L	H	Pseudo-Write Transfer

Table 1: Functional Truth Table

Note; H: VIH, L: VIL, *: VIH or VIL

(1) The input level of $\overline{DT}/\overline{OE}$ in the \overline{CAS} before \overline{RAS} timing is not ristricted. However it is recommended that $\overline{DT}/\overline{OE}$ be held 'High' because this input will be used for future expansion of the operation mode.

ADDRESSING

The 18 address bits required to decode 4-bits of the 1,048,576 cell locations within the Dynamic RAM memory array of the TC524257P/Z/J, are multiplexed onto 9 address input pins (A0 $^{\sim}$ A8). Nine row-address bits are latched on the falling edge of the row address strobe (\overline{RAS}) and the following nine column address bits are latched on the falling edge of the column address strobe (\overline{CAS}).

The row address inputs AX0 \circ AX3 are also used as operation code input signals in the raster operation set-up cycle.

DATA TRANSFER/OUTPUT ENABLE (DT/OE)

The $\overline{\text{DT}}/\overline{\text{OE}}$ input is a multifucntion pin. When $\overline{\text{DT}}/\overline{\text{OE}}$ is 'High' at the falling edge of $\overline{\text{RAS}}$, a normal DRAM cycle is performed and this input is used as an output enable. When $\overline{\text{DT}}/\overline{\text{OE}}$ is 'Low' at the falling edge of $\overline{\text{RAS}}$, a data transfer operation is started between the RAM port and the SAM port.

WRITE-PER-BIT/WRITE-ENABLE (WB/WE)

The $\overline{\text{WB}}/\overline{\text{WE}}$ input is also a multifunction pin. For conventional DRAM cycle, the $\overline{\text{WB}}/\overline{\text{WE}}$ input is used in the same manner as standard DRAMs except when the write-per-bit function or the raster operation are used. When $\overline{\text{WB}}/\overline{\text{WE}}$ is 'low' at the falling edge of $\overline{\text{RAS}}$, the bit write-mask is enabled. When $\overline{\text{WB}}/\overline{\text{WE}}$ and $\overline{\text{CAS}}$ are 'low' at the falling edge of $\overline{\text{RAS}}$, the raster operation set-up cycle is executed.

The $\overline{\text{WB}}/\overline{\text{WE}}$ input also determines the direction of data transfer between the DRAM memory array and the serial register. When $\overline{\text{WB}}/\overline{\text{WE}}$ is 'high' at the falling edge of $\overline{\text{RAS}}$, the data is transferred from RAM to SAM (read-transfer cycle). When $\overline{\text{WB}}/\overline{\text{WE}}$ is 'low' at the falling edge of $\overline{\text{RAS}}$, the data is transferred from SAM to RAM (write-transfer cycle).

WRITE-MASK DATA/DATA INPUT/OUTPUT (W1/IO1_to W4/IO4)

When the write-per-bit function is enabled, the mask data on the W1/IOl pins is latched into the write-mask register WMl at the falling edge of \overline{RAS} . Data is written into the DRAM on data lines where the write-mask data is a logic '1'. Writing is inhibited on data lines where the write-mask data is a logic '0'. The write-mask data is valid for only one cycle except for during raster operation. In the raster operation set-up cycle, the mask data is latched into the write-mask register WM2 at the falling edge of \overline{RAS} . The write-mask selected during the raster operation set-up cycle remains valid for all subsequent raster operation write, read-modify-write or page-mode write cycles.

PAGE MODE

The page mode feature of the TC524257P/Z/J allows data to be transferred into or multiple column locations of the same row by having multiple column cycles during a single active \overline{RAS} cycle.

For the initial page mode access, the output data is valid after the specified access time from $\overline{\text{RAS}}$. For all subsequent page mode read operations, the output data is valid after the specified access time from $\overline{\text{CAS}}$. As a result, page mode operation reduces power dissipation and improves data access time.

When the write-per-bit function is enabled, the mask data specified in the first write operation, at the falling edge of \overline{RAS} , is maintained throughout the page mode write cycle.

RAS-ONLY REFRESH

The data in the DRAM cycle requires periodic refreshing to prevent data loss. Refreshing is accomplished by performing a memory cycle at each of the 512 rows in the DRAM array within the specified 8ms refresh period. Although any normal memory cycle will perform the refresh operation, this function is most easily accomplished with ${}^{1}\overline{\text{RAS}}-\text{ONLY}{}^{1}$ cycles.

CAS-BEFORE-RAS REFRESH

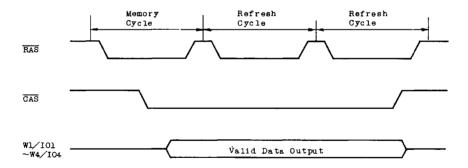
The TC524257P/Z/J also offers an internal refresh function. When $\overline{\text{CAS}}$ is held 'low' for a specified period (tcsr) before $\overline{\text{RAS}}$ goes low, an internal refresh address counter and on-chip refresh control clock generators are enabled and an internal refresh operation takes place. When the refresh operation is completed, the internal refresh address counter is automatically incremented in preparation for the next $\overline{\text{CAS}}$ -before- $\overline{\text{RAS}}$ cycle. For successive $\overline{\text{CAS}}$ -before- $\overline{\text{RAS}}$ refresh cycles, $\overline{\text{CAS}}$ can remain low while cycling $\overline{\text{RAS}}$.

During a $\overline{\text{CAS}}$ -before- $\overline{\text{RAS}}$ refresh cycle, $\overline{\text{WB}}/\overline{\text{WE}}$ must be 'high' at the falling edge of $\overline{\text{RAS}}$ to prevent a false raster operation set-up cycle from occurring.

HIDDEN REFRESH

A hidden refresh is a $\overline{\text{CAS}}$ -before- $\overline{\text{RAS}}$ refresh performed by holding $\overline{\text{CAS}}$ 'low' from a previous read cycle. This allows for the output data from the previous memory cycle to remain valid while performing a refresh. The internal refresh address counter provides the address and the refresh is accomplished by cycling $\overline{\text{RAS}}$ after the specified $\overline{\text{RAS}}$ -precharge period (refer to figure 1).

Figure 1: hidden refresh cycle



WRITE-PER-BIT FUNCTION

The write-per-bit function selectively controls the internal write-enable circuits of the RAM port. When $\overline{\text{WB}}/\overline{\text{WE}}$ is held 'low' at the falling edge of $\overline{\text{RAS}}$, during a random access operation, the write-mask is enabled. At the same time, the mask data on the Wi/IOi pins is latched onto the write-mask register (WM1). When a 'O' is sensed on any of the Wi/IOi pins, their corresponding write circuits are disabled and new data will not be wirtten.

When a '1' is sensed on any of the Wi/IOi pins, their corresponding write circuits will remain enabled so that new data is written. The truth table of the write-per-bit function is shown in table 2.

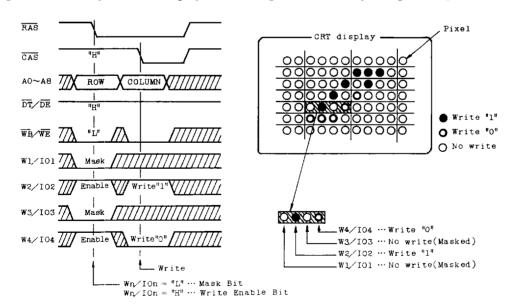
Table 2: Truth table for write-per-bit function

	At the	Function				
CAS	DT/OE	WB/WE	Wi/IOi (i=1 ~ 4)	Tunccion		
Н	н	Н	*	Write Enable		
н	н	L	1	Write Enable		
"		_	0	Write Mask		

An example of the write-per-bit function illustrating its application to displays is shown in figures 2 and 3.

Figure 2: write-per-bit timing cycle

Figure 3: corresponding bit-map



RASTER OPERATION

The TC524257P/Z/J features a logic function which provides 16 modes of raster operation. The desired logic function mode is selected during the raster operation set-up cycle and remains in effect until another selection is made. During raster operation, the TC524257P/Z/J performs internal logic operations when data is written through the RAM port. As shown in figure 4, the result (fj) of the logic operation, between the input data and the data residing in the accessed memory location is stored back in the accessed memory location.

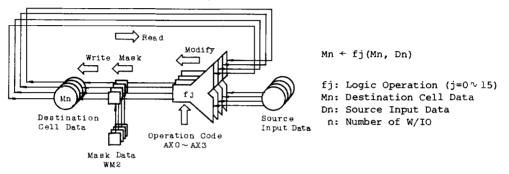


Figure 4: block diagram of raster operation

The row address inputs AXO thru AX3 are used as operation code input signals in the raster operation set—up cycle.

Table 3 lists the operation assigned to the sixteen logic function modes.

Operation Code			Code	Symbol	Operation	Note	Operation Code				Symbol	Operation	Note
EXA	AX2	AX1	AX0	Symbol	operation	Note	AX3	AX2	AX1	AX0	Symbol	Operation	Note
0	0	0	0	ZERO	0	*1	1	0	0	0	NOR	Dn + Mn	*2
0	0	0	1	AND1	Dn • Mn	*2	1	0	0	1	ENOR	Dn⊕Mn	*2
0	0	1	0	AND2	Dn • Mn	*2	1	0	1	0	INV1	Dn	*1
0	0	1	1	INHIBIT	Mn	*2	1	0	1	1	OR2	Dn + Mn	*2
0	1	0	0	AND3	Dn • Mn	*2	1	1	0	0	INV2	Mn	*2
0	1	0	1	*3THROUGH	Dn	*1	1	1	0	1	OR3	Dn + Mn	*2
0	1	1	0	EOR	Dn⊕Mn	*2	1	1	1	0	NAND	Dn • Mn	*2
0	1	1	1	OR1	Dn + Mn	*2	1	1	1	1	ONE	1	*1

Table 3: Truth table of raster operation

Note: *1 Normal write cycle timing is applied.

- *2 Raster operation write cycle timing must be applied.
- *3 The 'THROUGH' operation mode allows input data to be written directly into the selected memory location without raster operation. Therefore, 'THROUGH' is used to reset the raster operation.

Figure 5: Raster operation set-up cycle

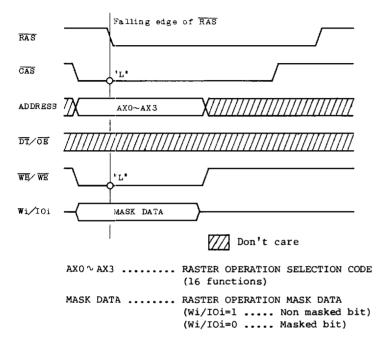
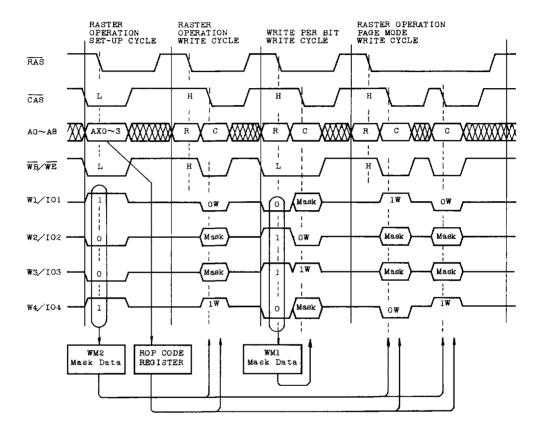


Figure 5 shows the timing diagram for the raster operation set-up cycle. Both $\overline{\text{CAS}}$ and $\overline{\text{WB}}/\overline{\text{WE}}$ must be low at the falling edge of $\overline{\text{RAS}}$. At this point, the operation code specified by row addresses AXO thru AX3 determines the logic function to be performed and the mask data is latched into the write-mask register WM2. The logic function and mask data specified during the raster operation set-up cycle will remain in effect during all subsequent raster operation cycles, till another raster operation set-up cycle is executed to change the logic operation mode and mask data.

When the 'THROUGH' operation mode is selected, a logic operation is not performed but the mask data specified during the raster operation set-up cycle remains in effect during all subsequent raster operation cycles (persistent write per bit function).

Figure 6 shows an example of raster operation cycles with a write-per-bit cycle mixed in the sequence. During the write-per-bit cycle, the raster operation is inhibited and the mask data in register WM1 is used while the mask data in register WM2 is ignored. In the subsequent raster operation page mode cycle, the raster operation is reactivated and the mask data in register WM2 is used again.

Figure 6: Example of raster operation



TRANSFER OPERATION

The TC524257P/Z/J features bi-directional transfer capability from RAM to SAM and from SAM to RAM. A transfer consists of loading 512 words by 4-bits of data from one port into the other. During a transfer cycle, RAM port and SAM port operations are restricted.

There are three types of transfer operations: read transfer, write transfer and pseudo-write transfer. As shown in table 4, the type of transfer operation is determined by $\overline{\text{CAS}}$, $\overline{\text{DT}}/\overline{\text{OE}}$, $\overline{\text{WB}}/\overline{\text{WE}}$ and $\overline{\text{SE}}$ at the falling edge of $\overline{\text{RAS}}$.

Table 4: Truth table of transfer operation

At th	ne falli	ng edge	of RAS		Transfer
CAS	DT/OE	WB/WE	SE		direction
Н	L	н	*	Read/real-time read transfer cycle	RAM → SAM
Н	L	L	L	Write-transfer cycle	SAM → RAM
Н	L	L	Н	Pseudo-write transfer cycle	_

*: high or low

READ-TRANSFER CYCLE

A read-transfer consists of loading a selected row of data from the RAM array into the SAM register. A read-transfer is accomplished by holding $\overline{\text{CAS}}$ high, $\overline{\text{DT}}/\overline{\text{DE}}$ low and $\overline{\text{WB}}/\overline{\text{WE}}$ high at the falling edge of $\overline{\text{RAS}}$. The row address selected at the falling edge of $\overline{\text{RAS}}$ determines the RAM row to be transferred into the SAM.

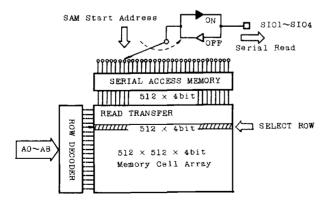
The actual data transfer completed at the rising edge of $\overline{DT}/\overline{OE}$.

When the transfer is completed, the SIO lines are set into the output mode.

In a read/real-time read-transfer cycle, the transfer of a new row of data is completed at the rising edge of $\overline{DT}/\overline{OE}$ and becomes valid on the SIO lines after the specified access time t_{SCA} from the rising edge of the subsequent serial clock(SC) cycle.

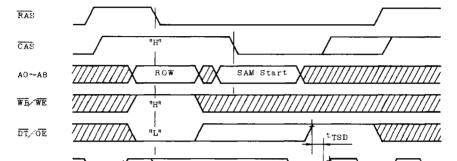
The start address of the serial pointer of the SAM is determined by the column address selected at the falling edge of $\overline{\text{CAS}}$. (refer to figure 7).

Figure 7: block diagram of RAM port and SAM port during read transfer



DATA-OUT

In a read-transfer cycle (which is preceded by a write-transfer cycle), the SC clock must be held at a constant $V_{\rm IL}$ or $V_{\rm IH}$, after the SC precharge time has been satisfied. A rising edge of the SC clock must not occur until after the specified delay $t_{\rm TSD}$ from the rising edge of $\overline{\rm DT}/\overline{\rm OE}$ (refer to Figure 8).



Inhibit rising transition

Figure 8: Read-transfer cycle (preceded by a write-transfer cycle)

In a real-time read-transfer cycle (which is preceded by another read-transfer cycle), the previous row data appears on the SIO lines until the specified $t_{\rm SCA}$ access time from the same rising edge of SC.

This feature allows for the first bit of the new row of data to appear on the serial output as soon as the last bit of the previous row has been strobed, without any timing loss. To make this continuous data flow possible: the rising edge of $\overline{\text{DT}}/\overline{\text{OE}}$ must be synchronized with $\overline{\text{RAS}}$, $\overline{\text{CAS}}$ and the subsequent rising edge of SC (refer to Figure 9).

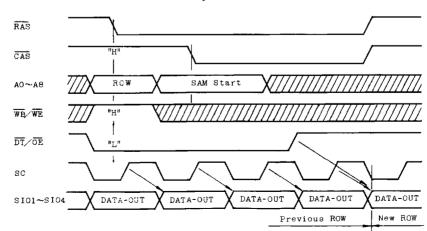


Figure 9: Real-time read transfer cycle

DATA-IN

SC

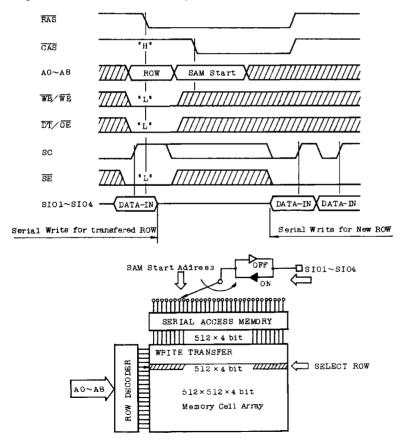
SI01~SI04

WRITE-TRANSFER CYCLE

A write-transfer cycle consists of loading the content of the SAM data register into a selected row of the RAM array. A write-transfer is accomplished by $\overline{\text{CAS}}$ high, $\overline{\text{DT}/\text{OE}}$ low, $\overline{\text{WB}/\text{WE}}$ low and $\overline{\text{SE}}$ low at the falling edge of $\overline{\text{RAS}}$. The row address selected at the falling edge of $\overline{\text{RAS}}$ determines the RAM row address into which the data will be transferred. The column address selected at the falling edge of $\overline{\text{CAS}}$ determines the start address of the serial pointer of the SAM. After the write-transfer is completed, the SIO lines are in the input mode so that serial data synchronized with SC can be loaded.

When two consecutive write-transfer operations are performed, there is a delay in availability between the last bit of the previous row and the first bit of the new row. Consequently the SC clock must be held at a constant $V_{\rm IL}$ or $V_{\rm IH}$ after the SC precharge time $t_{\rm SC}$ -has seen satisfied, a rising edge of the SC clock until after a specified delay $t_{\rm SRD}$ from the rising edge of $\overline{\rm RAS}$ (refer to figure 10).

Figure 10: Write-transfer cycle



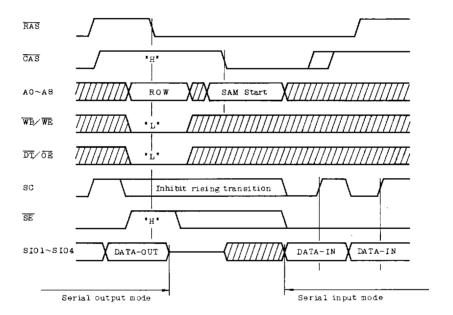
PSEUDO-WRITE-TRANSFER CYCLE

The pseudo-write-transfer cycle switches SIO lines from serial output mode to serial input mode. A pseudo-write-transfer is accomplished by holding \overline{CAS} high, $\overline{DT}/\overline{OE}$ low, $\overline{WB}/\overline{WE}$ low and \overline{SE} high at the falling edge of \overline{RAS} . The pseudo-write-transfer cycle must be performed after a read-transfer cycle if the subsequent operation is a write-transfer cycle.

LENGTH THE BETTER B

There is a timing delay associated with the switching of the SIO lines from serial output mode to serial input mode. During this period, the SC clock must be held at a constant $V_{\rm IL}$ or $V_{\rm IH}$ after the tSC precharge time has been satisfied. A rising edge of the SC clock must not occur until after the specified delay $t_{\rm SRD}$ from the rising edge of $\overline{\rm RAS}$ (refer to Figure 11).

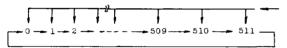
Figure 11: Pseudo-write-transfer cycle



SAM PORT OPERATION

The TC524257P/Z/J is provided with a 512-word by 4-bit serial access memory(SAM). High-speed read and write operation may be performed through the SAM port independent of the RAM port operations, except during transfer operations. The preceding transfer operation determines the direction of data flow through the SAM registers.

Data may be read out of the SAM port after a read-transfer cycle (RAM \rightarrow SAM) has been performed. Data can be shifted out of the SAM port starting at any of the 512-bit locations. This tap location corresponds to the column address selected a the falling edge of $\overline{\text{CAS}}$ during the read-transfer cycle. The SAM registers are configured as circular data registers. The data is shifted out sequentially starting from the selected tap location to the most significant bit and then wraps around to the least significant bit.



Tap location determined by column address of read-transfer cycle.

Subsequent real-time-read-transfer may be performed on-the-fly as many times as desired within the refresh constrainst of the DRAM memory array.

A pseudo-write-transfer cycle must be performed in order to write data into the SAM port. This cycle switches the SAM port operation from output mode to input mode. Data is not transferred during a pseudo-write-transfer cycle. A write-transfer cycle (SAM \rightarrow RAM) may then be performed. The data in the SAM registers is loaded into the RAM row selected by the row address at the falling edge of $\overline{\text{RAS}}$. The start address of SAM registers is determined by the column address selected at the falling edge of $\overline{\text{CAS}}$.

Table 5: Truth table for SAM operation

Preceding Transfer Cycle	SAM port operation	DT/OE (at the falling edge of RAS)	sc	SĒ	Function
read- transfer	serial output	Н*	7	L	enable serial read
Clauster	mode			Н	disable serial read
write- transfer	serial	n.	Л	L	enable serial write
cranster	input mode			Н	disable serial write

^{*} When simultaneous operation are being performed on the RAM port and the SAM port, $\overline{DT}/\overline{OE}$ must be held high at the falling edge of \overline{RAS} so as not to perform a false trasnfer cycle.

SERIAL CLOCK (SC)

All operations of the SAM port are synchronized with the serial clock SC. Data is shifted in or out of the SAM registers at the rising edge of SC. In a serial-read, the output data becomes valid on the SIO pins after the maximum specified serial access time $t_{\rm SCA}$ from the rising edge of SC.

The serial clock SC also increments the 9-bit serial pointer which is used to select the SAM address. The pointer address is incremented in a wrap-around mode to select sequential locations after the starting location which is determined by the column address in the read-transfer cycle. When the pointer reaches the most significant address location (decimal 511), the next SC clock will place it at the least significant address location (decimal 0).

SERIAL ENABLE (\overline{SE})

The \overline{SE} input is used to enable serial access operation. In a serial-read cycle, \overline{SE} is used as an output control. In a serial-write cycle, \overline{SE} is used as a write enable control. When \overline{SE} is high, serial access is disabled, however, the serial address pointer location is still incremented when SC is clocked even when \overline{SE} is high.

SERIAL INPUT/OUTPUT (SIO1 ~ SIO4)

Serial input and serial output share common I/O pins. Serial input or output mode is determined by the most recent transfer cycle. When a read-transfer cycle is performed, the SAM port is in the output mode. When a pseudo-write cycle is performed, the SAM port operation is switched from output mode to input mode.

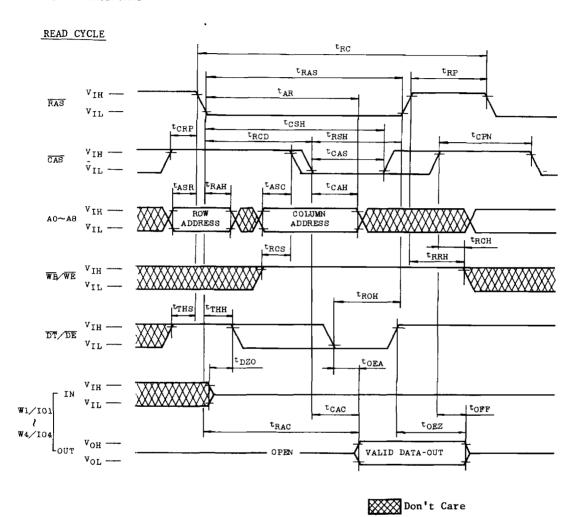
During subsequent write-transfer cycle, the SAM port remains in the input mode.

REFRESH

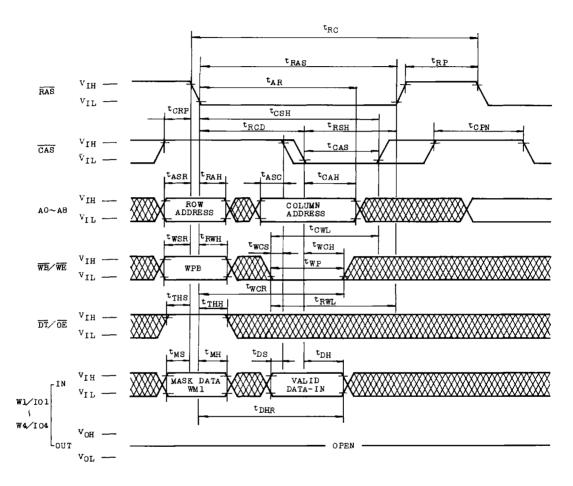
The SAM data registers are static flip-flops therefore a refresh is not required.

TC524257P/Z/J-10, TC524257P/Z/J-12

TIMING WAVEFORMS

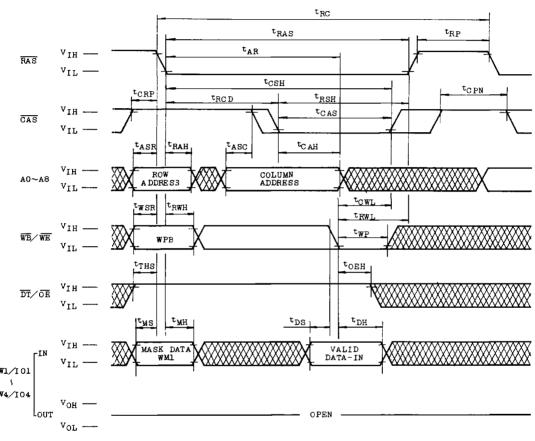


WRITE CYCLE (EARLY WRITE)



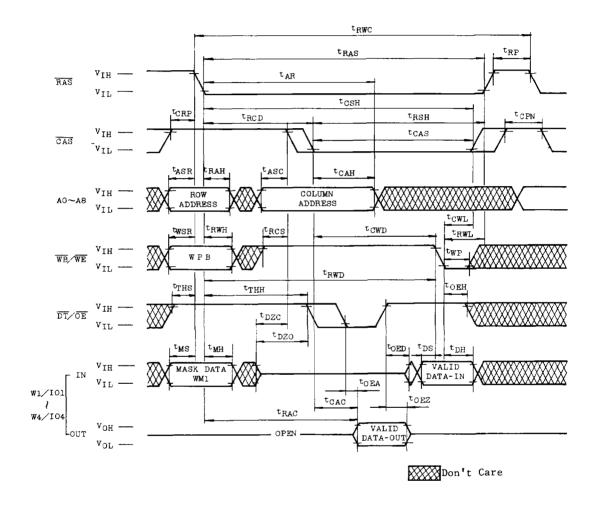
Don't Care

WRITE CYCLE (OE CONTROLLED WRITE)

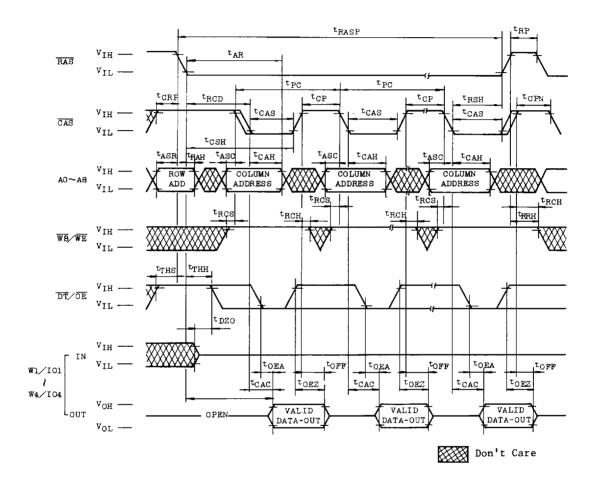


Don't Care

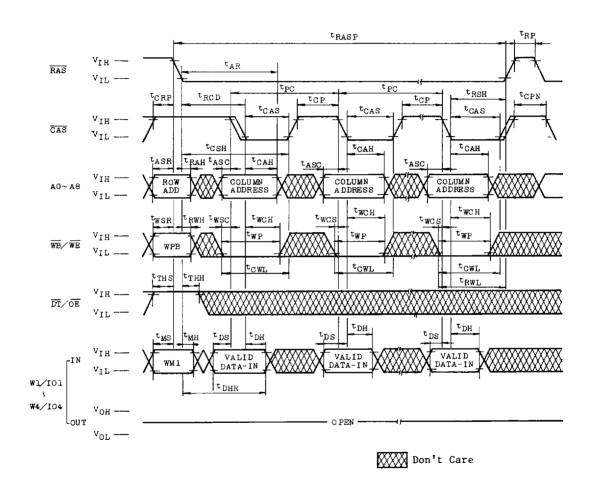
READ-WTITE/READ-MODIFY-WRITE CYCLE



PAGE MODE READ CYCLE

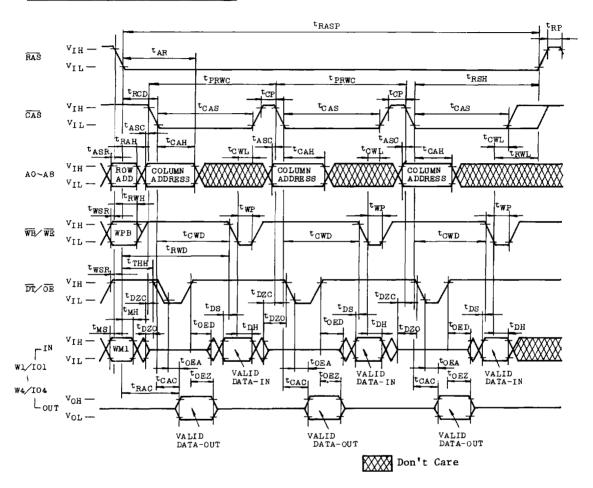


PAGE MODE WRITE CYCLE (EARLY WRITE)

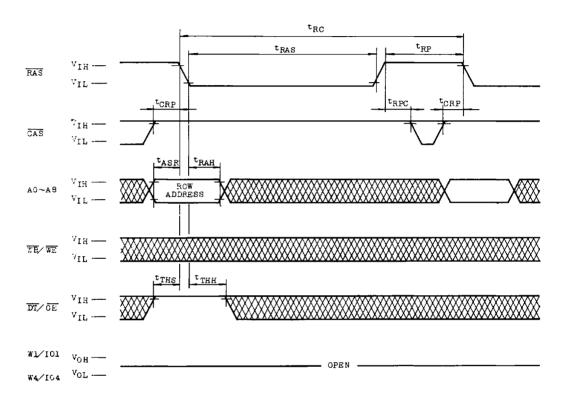


10. 在各种主要的支持性,但是有关的,我们就是一种的主要的,我们就是一种的主要的,我们就是一个人,我们就是一个人的,我们就是一个人的,我们就是一个人的。这一个

PAGE MODE READ-MODIFY-WRITE CYCLE

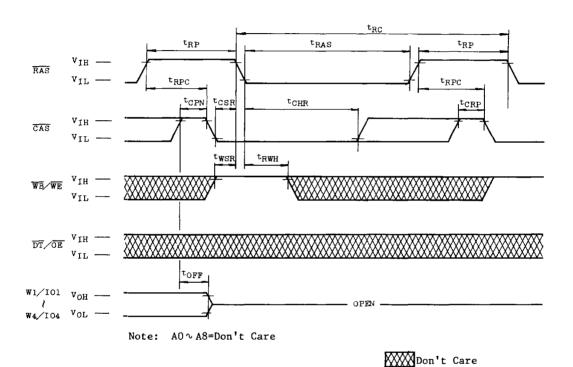


RAS ONLY REFRESH CYCLE

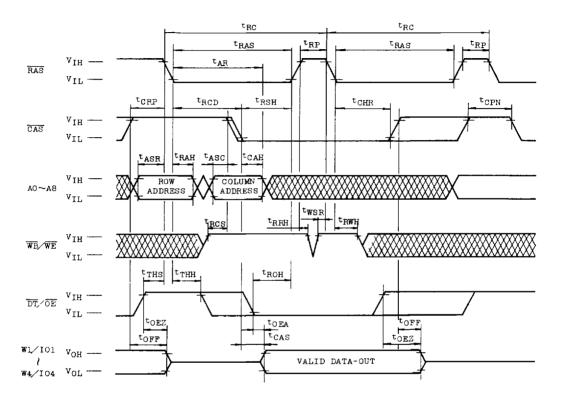


Don't Care

CAS BEFORE RAS REFRESH CYCLE



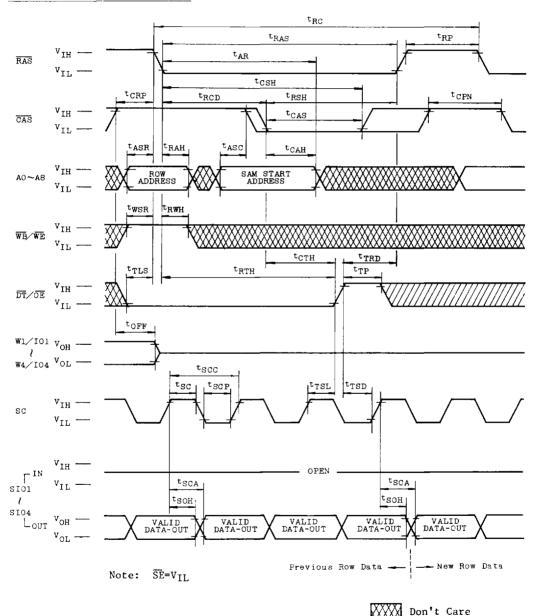
HIDDEN REFRESH CYCLE



2000年,1915年,在1916年,1916年,1916年,1916年,1916年,1916年,1916年,1916年,1916年,1916年,1916年,1916年,1916年,1916年,1916年,1916年,1

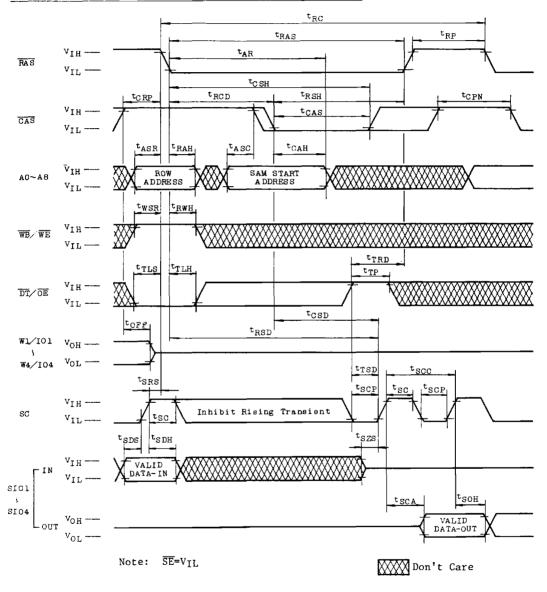
Don't Care

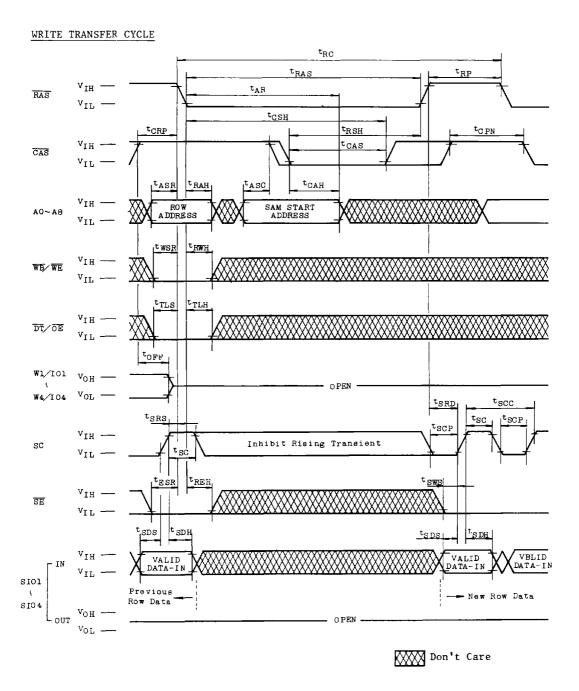
REAL TIME READ TRANSFER CYCLE



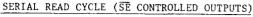
Notification of the state of th

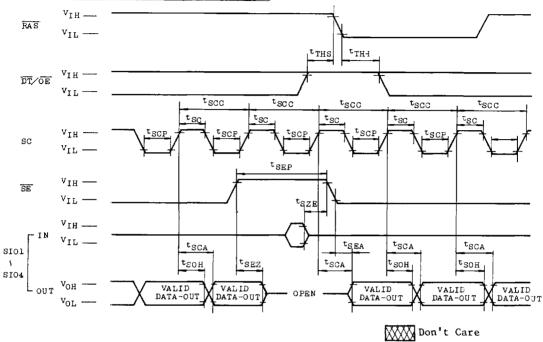
READ TRANSFER CYCLE (Previous transfer is write transfer)



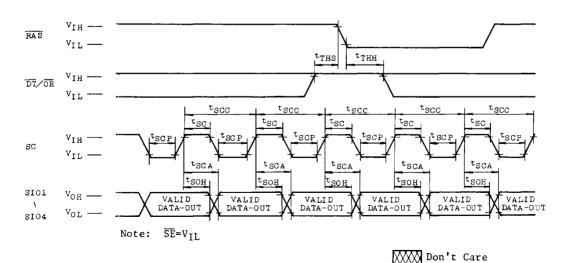


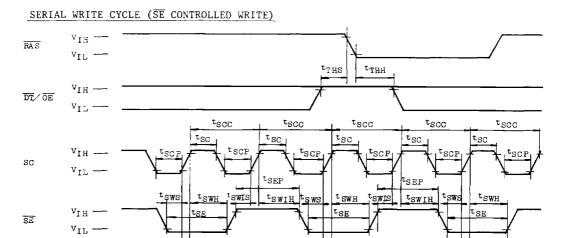
PSEUDO WRITE TRANSFER CYCLE tRAS t_{RP} VIH t_{AR} RAS VIL tcsh tCRP tRSH CAS t_{RAH} t_{CAH} t_{ASR} t_{ASC} ROW ADDRESS SAM START A0~A8 twsR tRWH t_{TLS} t_{TLH} DT/OE torr W1/101 - OPEN ν_{or} --W4/I04 tscc tSRS t SC P tsc VIH --tscp Inhibit Rising Transient SC tsws tREH tESR VIH -SE VIL tsDD tsDs tsDH tsDZ tsez VALID DATA-IN tSCA SIOL tsoH SI04 VALID DATA-OUT VALID OPEN DATA-OUT Serial Serial Input Mode Output Mode Don't Care





SERIAL READ CYCLE (SE=VIL)





t_{SDS}

tSDH

- OPEN

VALID

DATA-IN

tsDH

VALID

ts Ds

Don't Care

tsDs

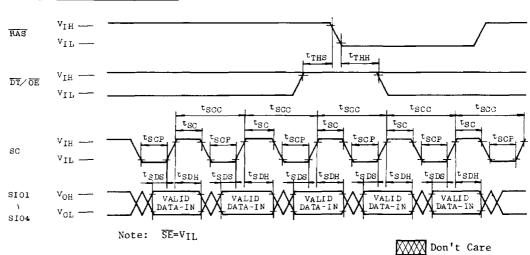
tsDH

VALID

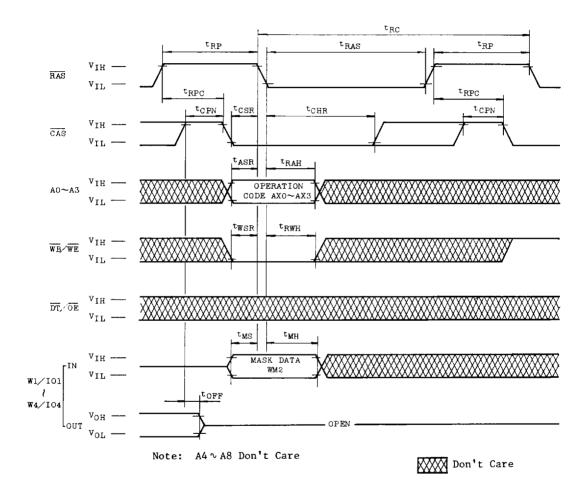
SERIAL WRITE CYCLE (SE=VIL)

V_{OH} ---

SIO1 5

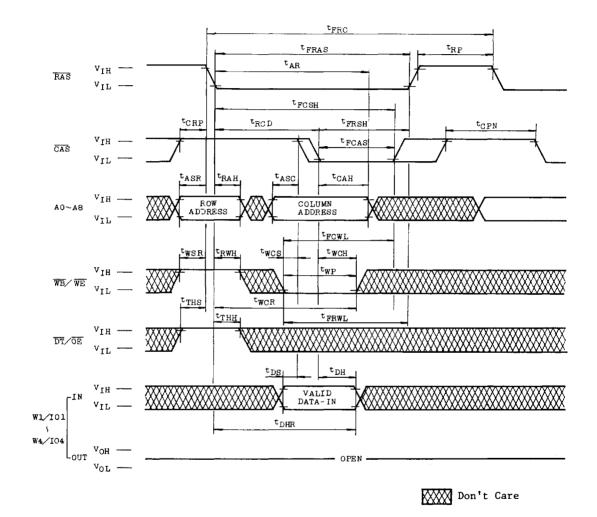


RASTER OPERATION SET-UP CYCLE



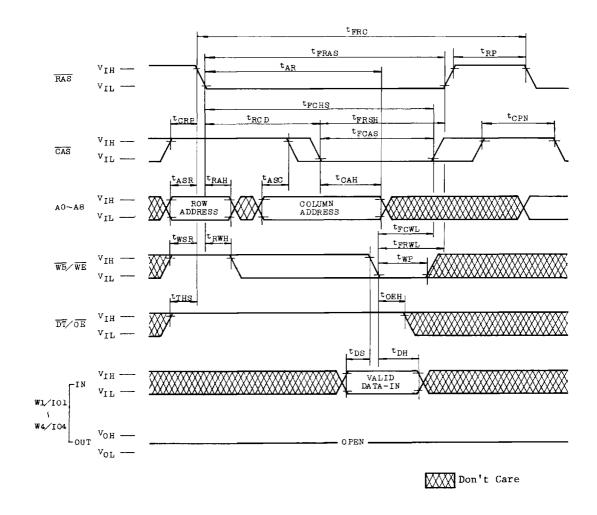
等。在16年8月中的特别的特别的**是**的特别的的最高的是一种的特别的人,但是一个人的人的人,但是一个人的人的人,但是一个人的人的人,也是一个人的人的人,也是一个人的

RASTER OPERATION WRITE CYCLE (EARLY WRITE)

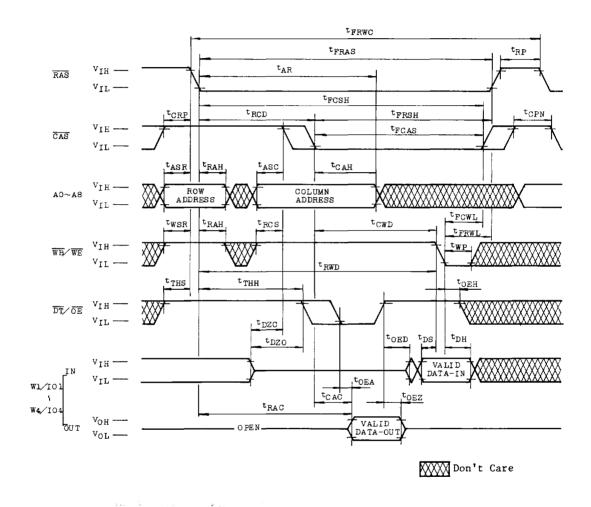


是是是这种的。我们是我们的一个人,我们就是我们的一个人,我们就是我们的一个人,我们就是我们的一个人,我们就是我们的一个人,我们就是我们的一个人,我们就是我们的一

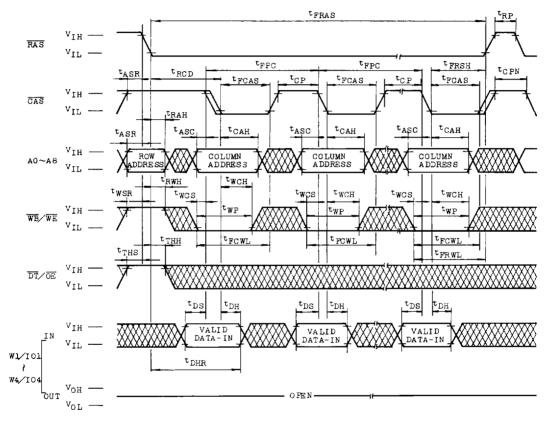
RASTER OPERATION WRITE CYCLE (OE CONTROLLED WRITE)



RASTER OPERATION READ-WRITE/READ-MODIFY-WRITE CYCLE



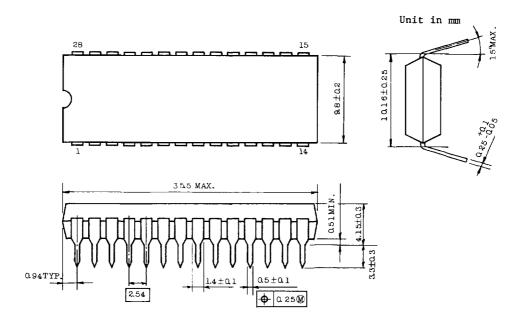
RASTER OPERATION PAGE MODE WRITE CYCLE



Don't Care

OUTLINE DRAWINGS

Plastic DIP

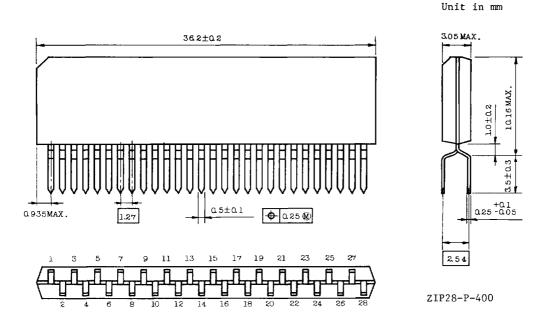


Note: Each lead pitch is 2.54mm.

All leads are located within 0.25 mm of their true longitudinal position with respect to No.1 and No.28 leads.

All dimensions are in millimeters.

Plastic ZIP



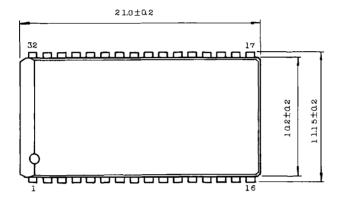
Note: Each lead pitch is 1.27mm.

All dimensions are in millimeters.

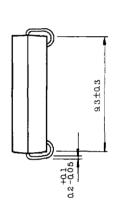
Toshiba does not assume any responsibility for use of any circuitry described; no circuit patent licenses are implied, and Toshiba reserves the right, at any time without notice, to change said circuitry.

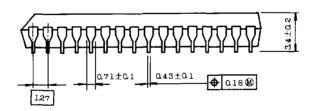
· Plastic SOJ

Unit in mm



CONTROL OF THE PROPERTY OF THE





SOJ32-P-400

Note: Each lead pitch is 1.27mm

All dimensions are in millimeters.